

Notice of References Cited	Application/Control No. 09/757,491	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Jennifer T Nguyen	Art Unit 2674	Page 1 of 1

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	C	US-5,349,366	09-1994	Yamazaki et al.	345/92
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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